

Notice of References Cited	Application/Control No. 10/602,377	Applicant(s)/Patent Under Reexamination CHIU ET AL.	
	Examiner Cynthia Britt	Art Unit 2138	Page 1 of 1

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	C	US-5,954,831 A	09-1999	Chang, Edward C. M.	714/720
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NON-PATENT DOCUMENTS

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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.